



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No.09/805,620
Confirmation No.3004
Filing Date March 13, 2001
Inventorship Craig M. Carpenter
Assignee Micron Technology, Inc.
Group Art Unit 1762
Examiner Eric B. Fuller
Attorney's Docket No. MI22-1563
Customer No. 021567
Title: Chemical Vapor Deposition Methods (As Amended)

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449


In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. Pursuant to 37 C.F.R. 1.98(a)(2)(ii), no copies of cited U.S. patents or U.S. patent application publications are included. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed before the mailing of a first office action after the filing of a Request for Continued Examination. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

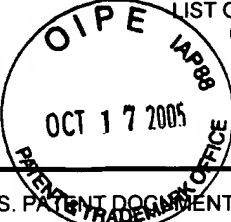
Respectfully submitted,

Dated: 17 Oct 2005

By: _____


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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1563		SERIAL NO. 09/805,620	
<div style="text-align: center;">  <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p> </div>				APPLICANT: Craig M. Carpenter et al.			
				FILING DATE March 13, 2001		GROUP 1762	
U.S. PATENT DOCUMENTS							
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,275,976	01/1994	Moslehi			
	AB	5,304,279	04/1994	Coultas et al.			
	AC	5,468,298	11/1995	Lei et al.			
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AK						
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AM						
	AN						
	AO						
EXAMINER		DATE CONSIDERED					
<p><small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small></p>							